



TÜV SÜD Rail

Multicore Devices in Safety
Applications -
Normative Aspects



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- Definition
- System architectures
- Normative aspects
- Avoidance of systematic failures
- Fault Detection



A **multi-core processor** is a single computing component **with two or more independent actual processing units** (called "cores"), which are the units that **read and execute program instructions**.

Source: wikipedia

Multi-core technology refers to CPUs that contain two or more **processing cores**. These cores operate as separate processors within a single chip. By using multiple cores, processor manufacturers **can increase the performance** of a CPU **without raising the processor clock speed**.

Source: <http://techterms.com/definition/multi-core>

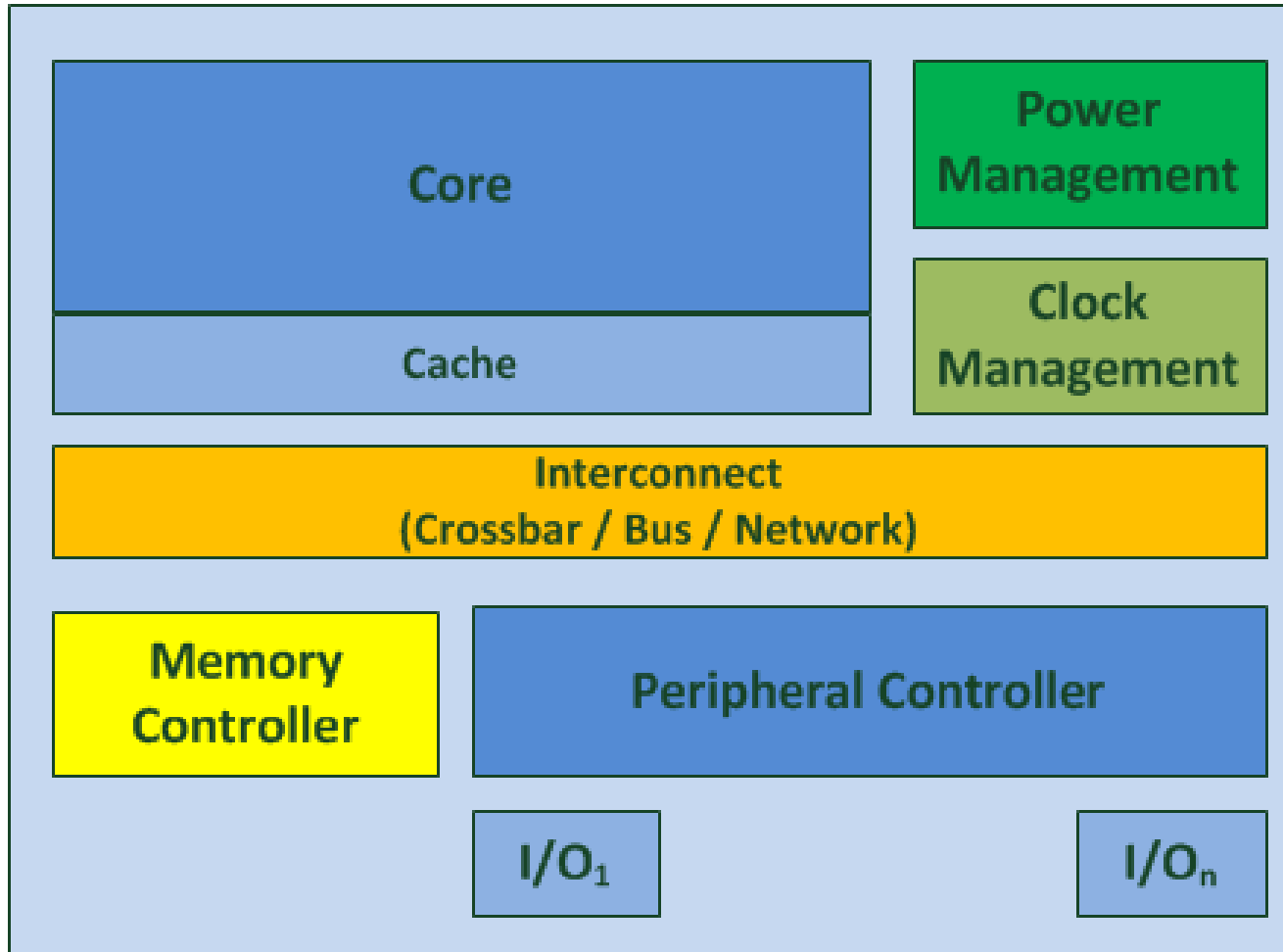
A multi-core processor is an integrated circuit (IC) **to which two or more processors** have been attached for **enhanced performance, reduced power consumption, and more efficient** simultaneous processing of multiple tasks.

Source: <http://searchdatacenter.techtarget.com/definition/multi-core-processor>

Single Core versus Multi Core



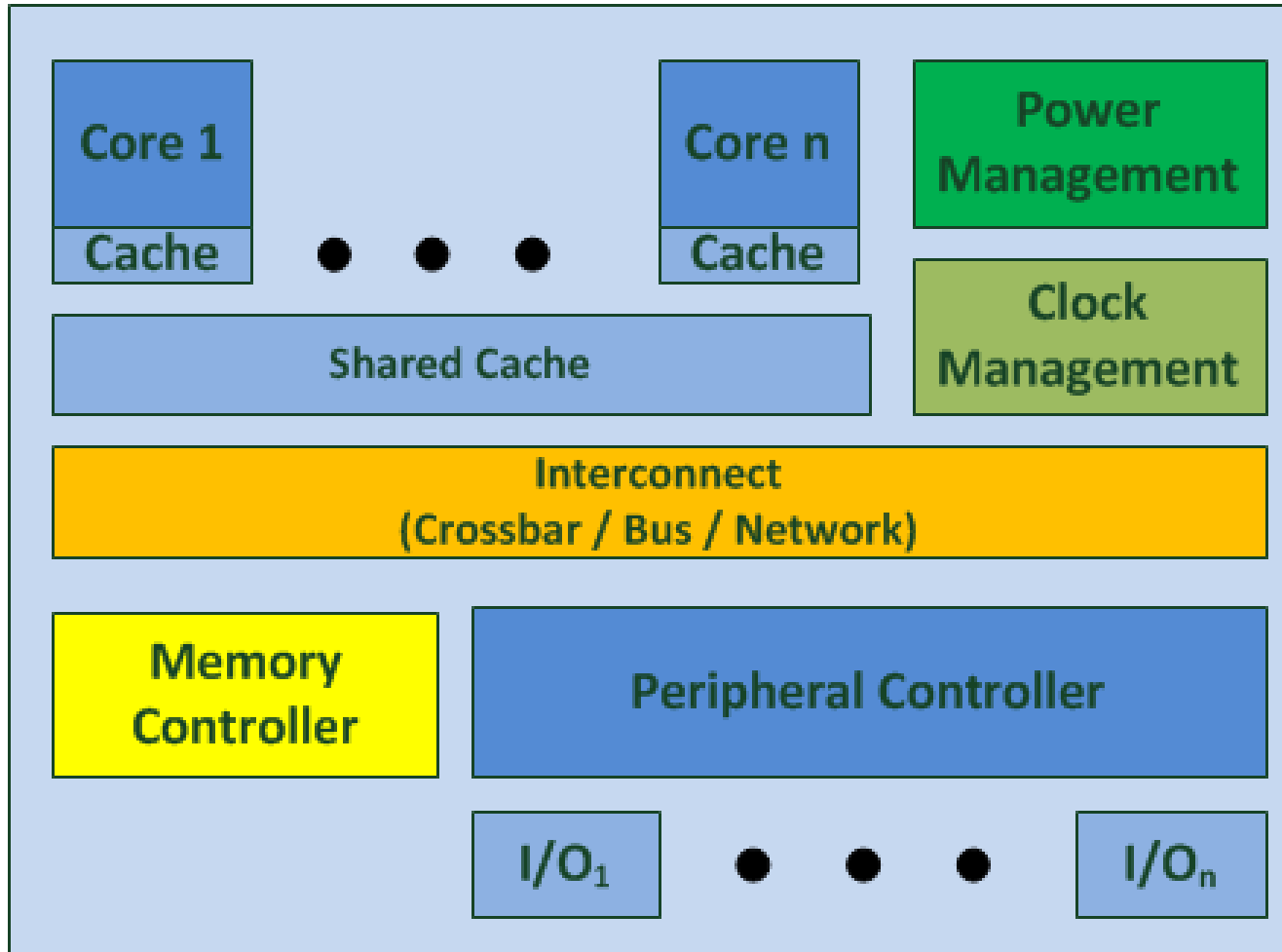
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Single Core versus Multi Core



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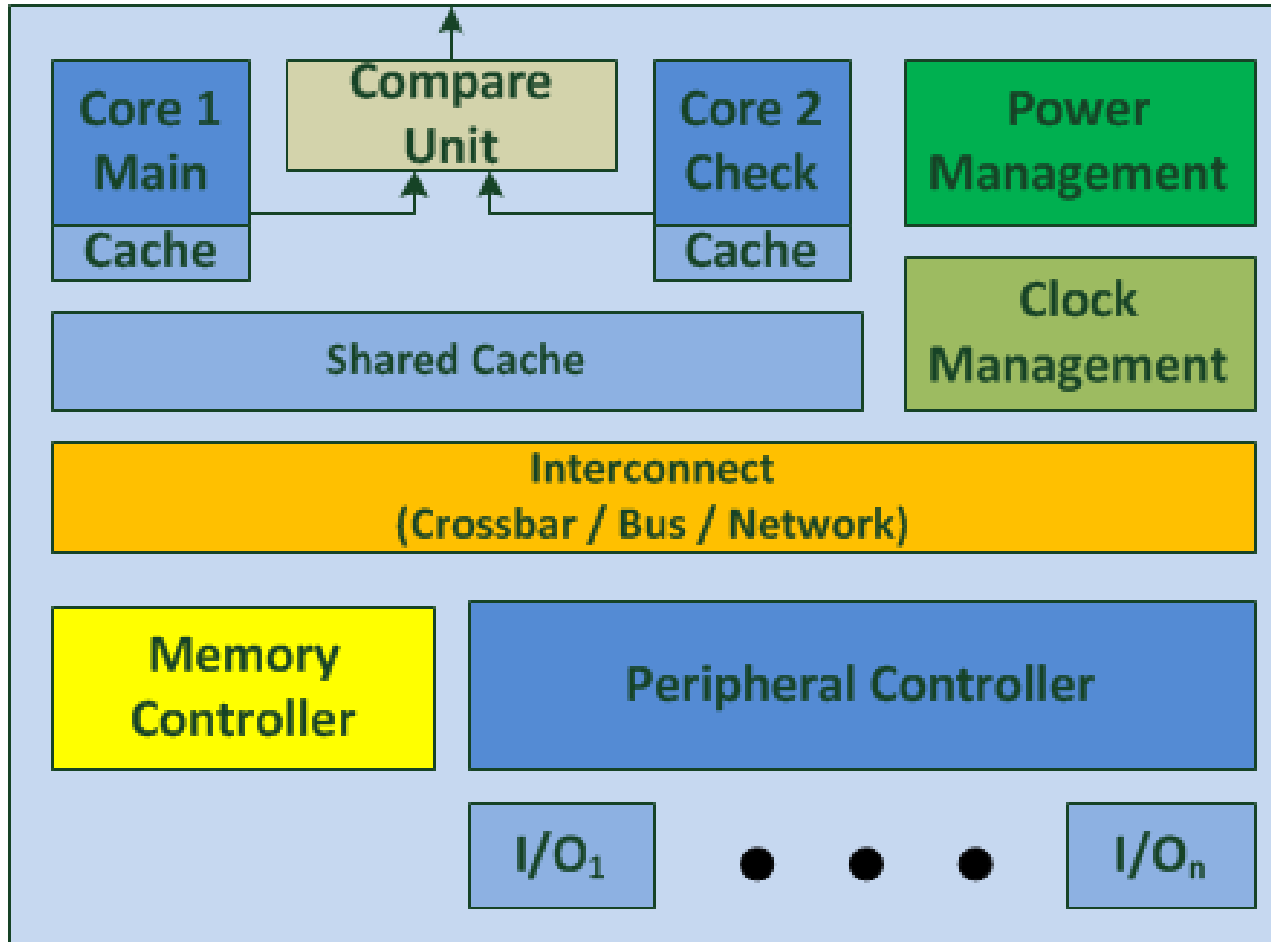


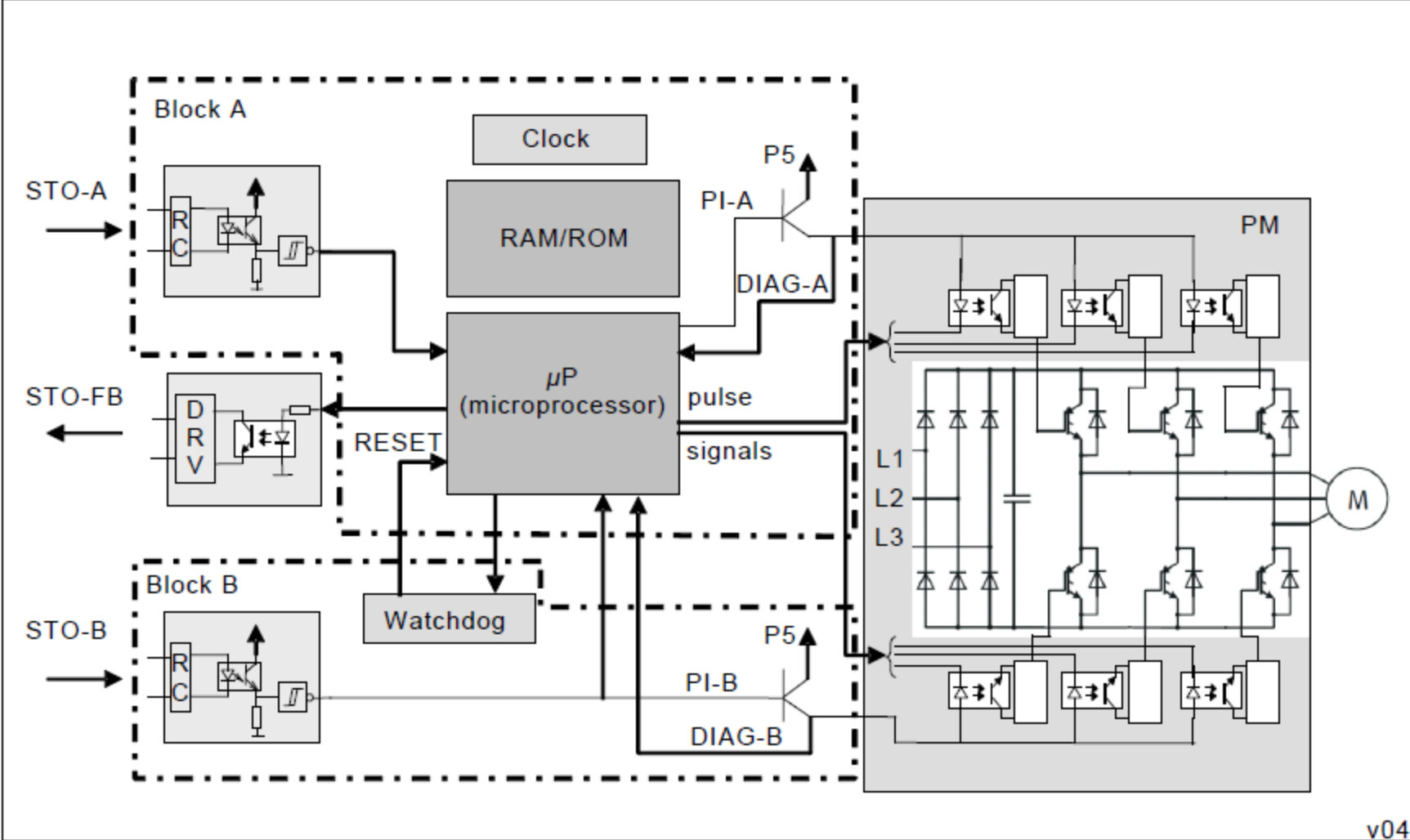
Source: <http://cacm.acm.org/magazines/2010/2/69360-managing-contention-for-shared-resources-on-multicore-processors/fulltext>

Different Architectures at Multicore Level



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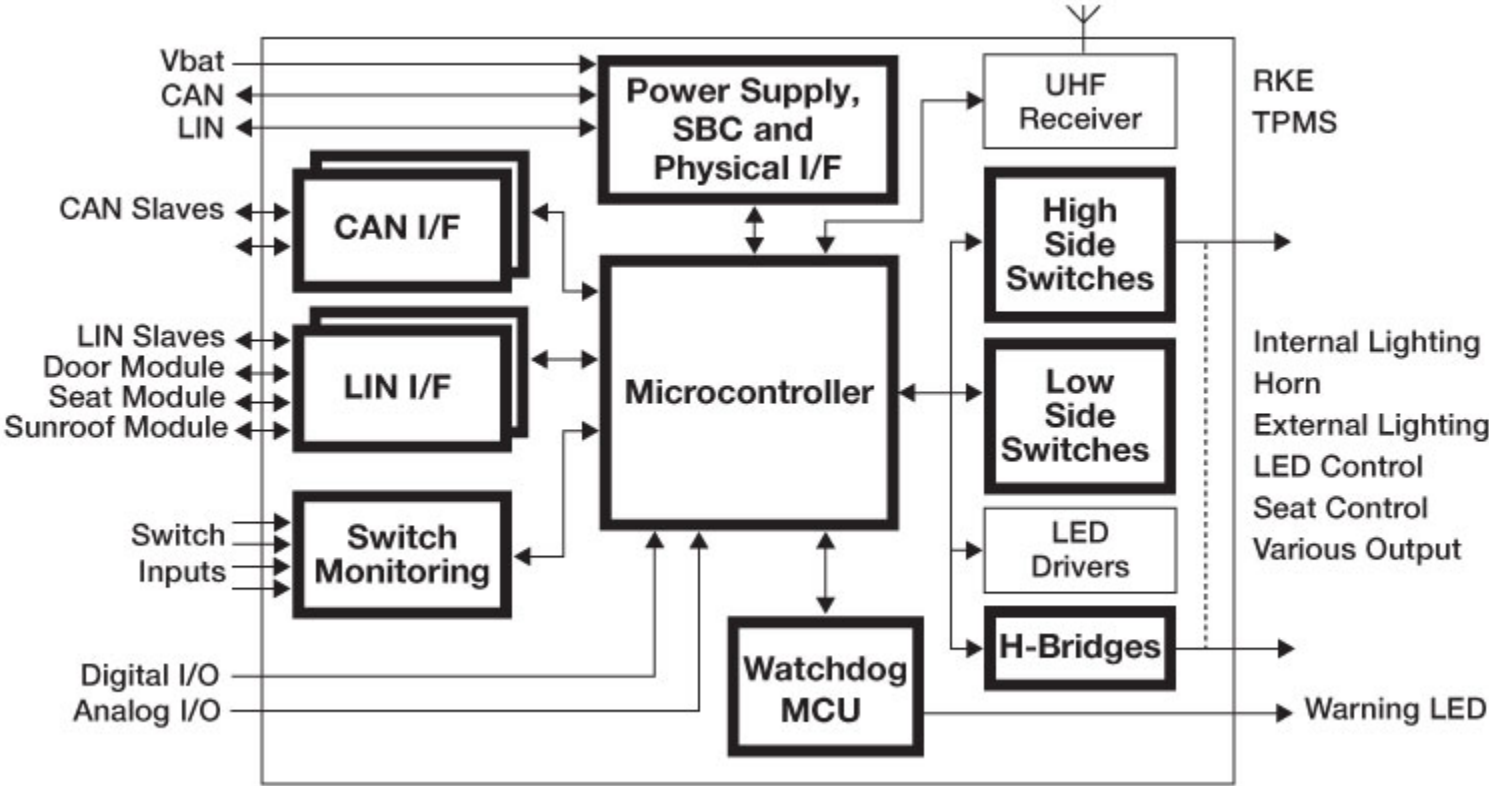
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2 Channels (Multicore only in one channel)

Different architectures in different industries - Automotive



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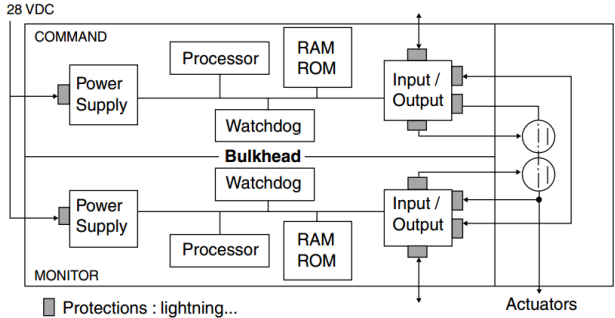
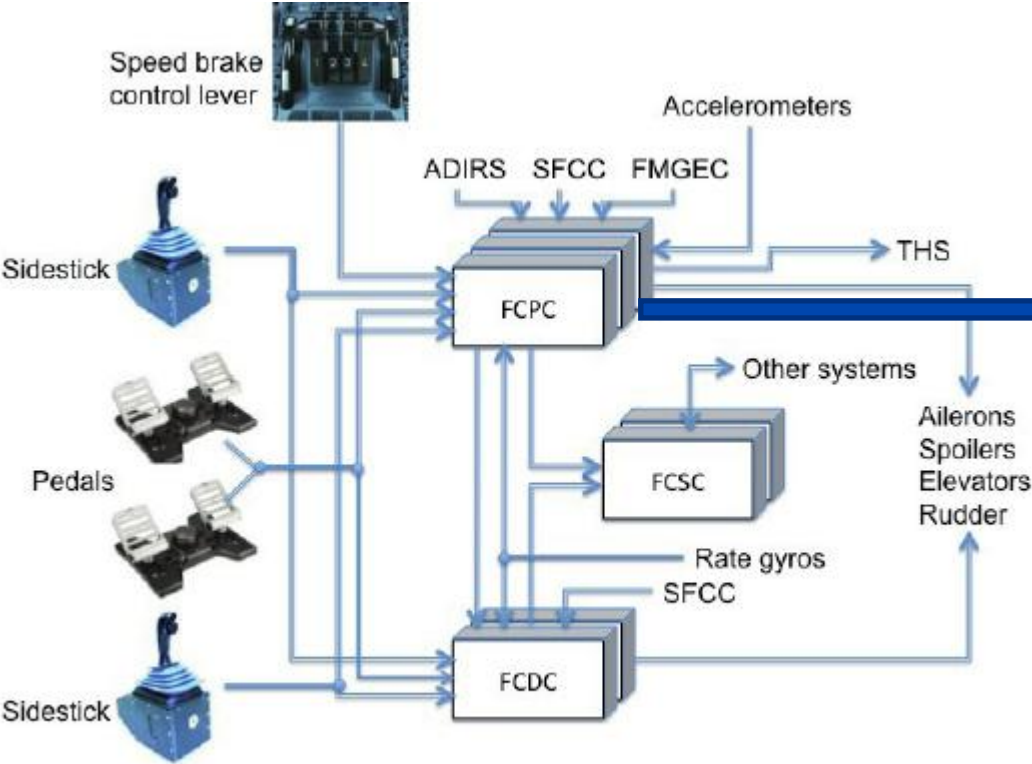


Once channel with supervision (watchdog)

Different architectures in different industries - Avionic



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Redundant system architecture (high availability)



- Safety Lifecycle, avoidance of systematic failures
- Failure modes
- Design related requirements, control of failures
- Verification



- According to IEC 61508-2:2010 no specific requirements for mass-produced electronic integrated circuits are defined.
- It is assumed that the avoidance of systematic failures is ensured by:
 1. Stringent development procedures
 2. Rigorous Testing
 3. Significant feedback from users
- If this assumption is not applicable the requirements for ASICs (see 7.4.6.7 and informative Annex F) will apply

See IEC 61508-2:2010 7.4.6.1 Note



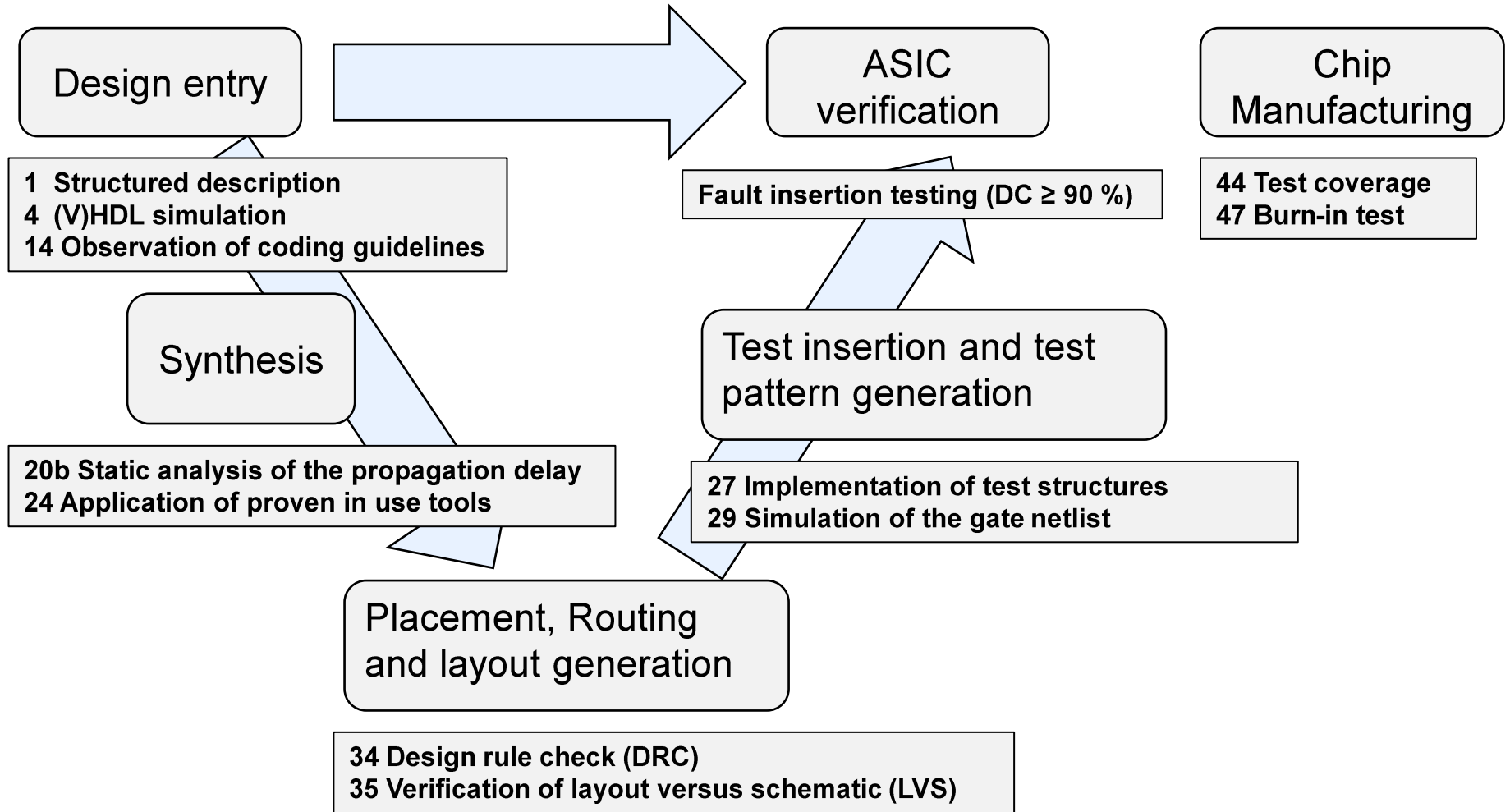
- ISO 26262-10:2011 Annex A contains examples about how to deal with microcontrollers in the context of automotive applications
- Two example approaches to provide evidence related to avoidance of systematic failures during design of a microcontroller are shown:
 1. Use measures defined in table A.8 of ISO 26262-10:2011
 2. Providing rationale by field data of similar products

See ISO 26262-10:2011 chapter A.3.7
- ISO/PDPAS 19451-2 : Application of hardware qualification

ASIC Safety Lifecycle



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IEC 61508-2:2010 Annex A:

- DC fault model
- Change of information caused by soft-errors
- Dynamic cross-over for memory cells
- No definite failure assumption
- Common Cause faults

ISO 26262-5:2011 Annex D

- D.C. fault model
- Soft error model
- Wrong coding, wrong or no execution
- Dependent faults

ISO 13849-2:2012 Annex D

- Undetected faults

- **ISO 26262-1, 1.22: dependent failures**
- *„Failures whose probability of simultaneous or successive occurrence cannot be expressed as the simple product of the unconditional probabilities of each of them“*
 - Note: *„Dependent failures include common cause failures and cascading failures“*
 - **1.13: Cascading failure:** failure of one item causes other elements to fail
 - **1.14: Common cause failure:** failure of two or more elements resulting from a single event or root cause
- **IEC 61508-4,**
 - **3.6.9: dependent failure:** *„failure whose probability cannot be expressed as the simple product of the unconditional probabilities of the individual events that caused it“*
 - **3.6.10: common cause failure:** *„failure, that is the result of one or more events, causing concurrent failures of two or more separate channels in a multiple channel system, leading to system failure“*
 - **IEC 61508-6:** Common cause failure considerations (“ **β -factor**”) include dependent failures

IEC 61508-2:2010 and ISO 13849-2:2012

- Annex E - requirements for integrated circuits (ICs) with on-chip redundancy e.g.:
 - > Separate physical blocks on substratum of the IC shall be established for each channel and each monitoring element
 - > The minimum distance between boundaries of separate physical blocks shall be sufficient
 - > The common cause potential of common resources such as boundary scan circuitries shall be analyzed.
 - > The estimated β_{IC} shall not exceed 25 %.
- ISO 26262 - ISO/PDPAS 19451-1: Application of concepts
 - > chapter 7 Multi-core components and ISO 26262
 - > Physical separation by using e.g. guard rings, separate wells,



IEC 61508-2:2010:

- Fault insertion testing (DC \geq 90 %)

ISO 26262-5:2011

- Fault injection testing for ASIL C/D

Verification of diagnostics on IC level is not yet fully defined in the standards.



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